Status of High Energy Irradiation Facilities in Europe

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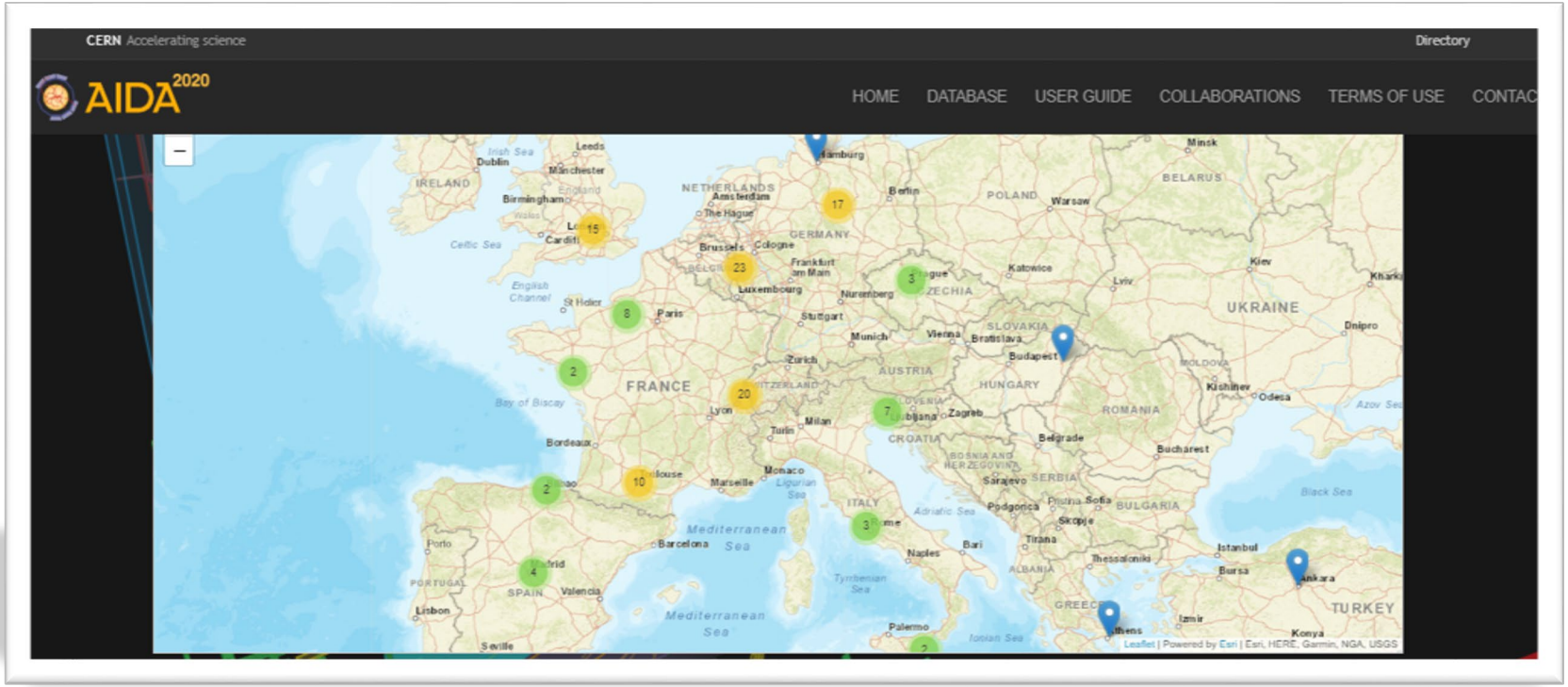
Facilities (worldwide from CERN database)

https://irradiation-facilities.web.cern.ch/

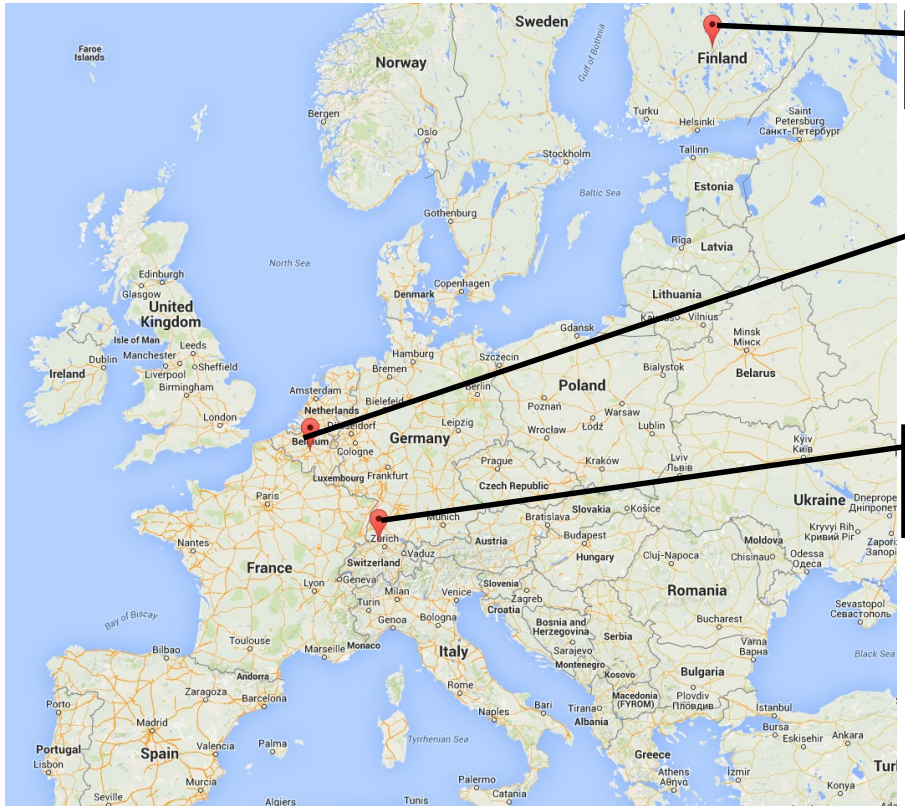


SEE testing in Europe

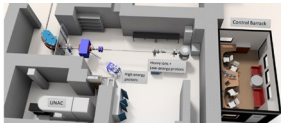
Standard Energy	<10 MeV/n
High Energy	10 - 100 MeV/n
Very High Energy	100 MeV/n – 5 GeV/n
Ultra High Energy	5-150 GeV/n

Facilities	Energy (MeV/nucleon)	Available cocktail	Availability per year for EEE Testing
UCL HIF (Louvain-la- Neuve, Belgium)	8-10 MeV/n	9 species from C to Xe	About 16 weeks
RADEF (Jyväskylä,Finland)	22 MeV/n , 16.3 MeV/n, 9.3 MeV/n before	O, Fe, Kr 6 ion species, from O to Xe (7 ion species,from N to Xe)	800 hr/year
KVI CART (Groningen, Netherlands)	30 MeV/n	4 species, from Ne to Xe	Currently closed under maintenance. To reopen in May 2021
GANIL G4 (Caen, France)	27 to 60MeV/n	One species per experiment, Ar, Kr, Xe or Pb	1-2 weeks
GSI SIS18 (Darmstadt, Germany)	50 MeV/n to 1-1.5 GeV/n	One species per experiment, can be from proton to U	Less than 1 week Only scientific experiments to be approved
CERN CHARM or North Area (Geneva, Switzerland)	6-160 GeV/nucleon	One species per experiment	Less than 1 week

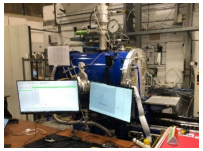
Irradiation test facilities (supported by ESA) – Heavy ions and protons and electrons



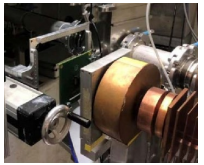
RADEF, JYFL Heavy ions, protons, electrons
Jyväskylä, Finland



UCL Heavy ions, protons
Louvain-la-Neuve
Belgium



PSI Protons, electrons
Villigen Switzerland

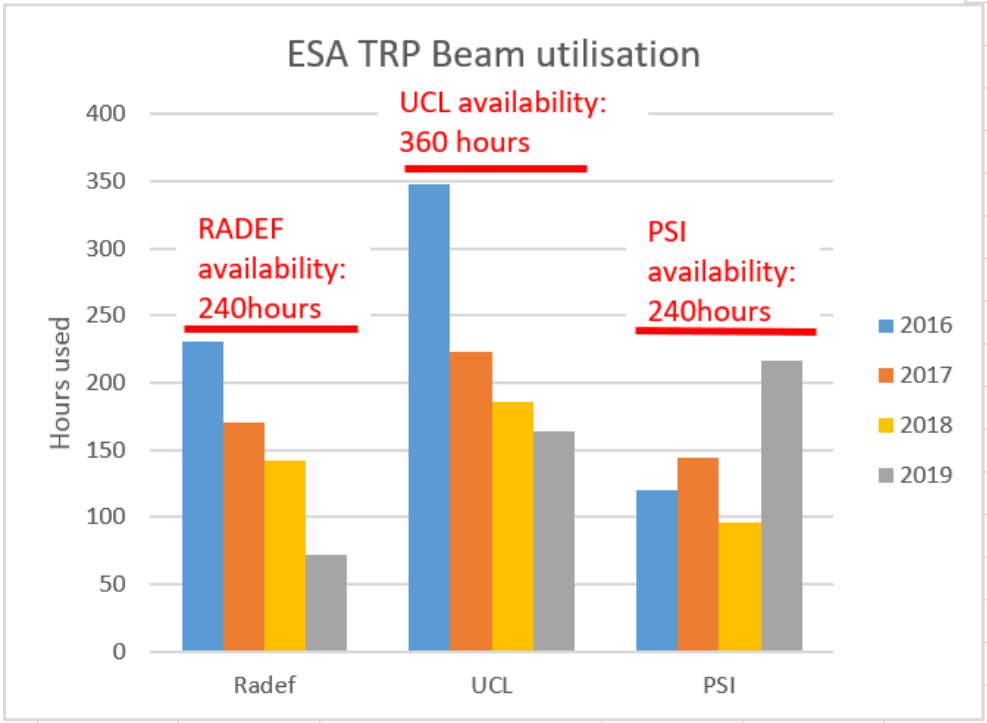


TEC-QEC has been collaborating with these facilities for more than 25 years. PSI, UCL, since 1990-1992. RADEF since 2004 beam in 2007-2008

Aiming at continuous improvement of the quality of the beam, dosimetry and testing infrastructure

Stable flux and energy levels, high particle selectivity, accurate dosimetry, electrical/optical interfaces for cabling

ESA beamtime at supported facilities



Aim at support facilities developments on **beam quality, dosimetry and** includes an annual fixed amount of hours for irradiations tests for

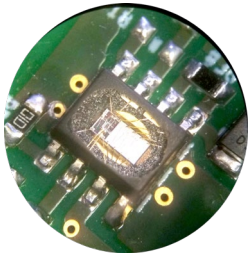
ESA R&D developments

2021_02_24 CMOS image sensor development
2021_02_23 SDRAM memories
2021_02_23 SiC qualification and other mosfet screening
2021_02_18 TIR(detector)
2021_01_21 HERA
2020_10_07 ASIC
2021_01_18 GaN MIM Capacitors
2020_12_11 Small study - intradie SRAM testing
2021_11_24 HERA - cubesat payload only
2020_11_23 SEE laser COTS screening
2020_11_22 FYS
2020_11_02 MEMS pressure modues
2020_10_16 Latchup testing of digital isolator
2020_10_09 GPU

2020_09_28 Phototransistor
2020_09_08 RACOCO
2020_09_07 MPCG
2020_09_06 GPU processors
2020_09_04 RADEM
2020_09_03 3Dnand
2020_09_01 GaN Devices
2020_09_02 SET
2020_09_01 Stuck bits on SDRAM
2020_08_31 Optical Fibers
2020_08_30 Stuck bits on SDRAM
2020_08_10 Proba 3
2020_08_09 NG-LARGE
2020_08_08 NG-ULTRA

Challenges : limited range of heavy ions

Standard energy ions
require sample preparation
to reach the active area with sufficient LET for testing
=>It may be not technically possible for certain technologies



delidding/decapping
or Die thinning for flip chip

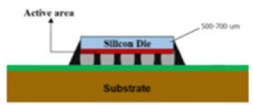
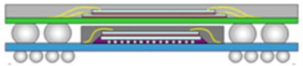
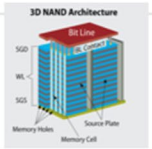
One common particularity of EEE COTS components is the dense packaging

Examples:

- Multi chip modules
- Flip chip construction
- Hybrids
- Plastic package with Cu bondwires

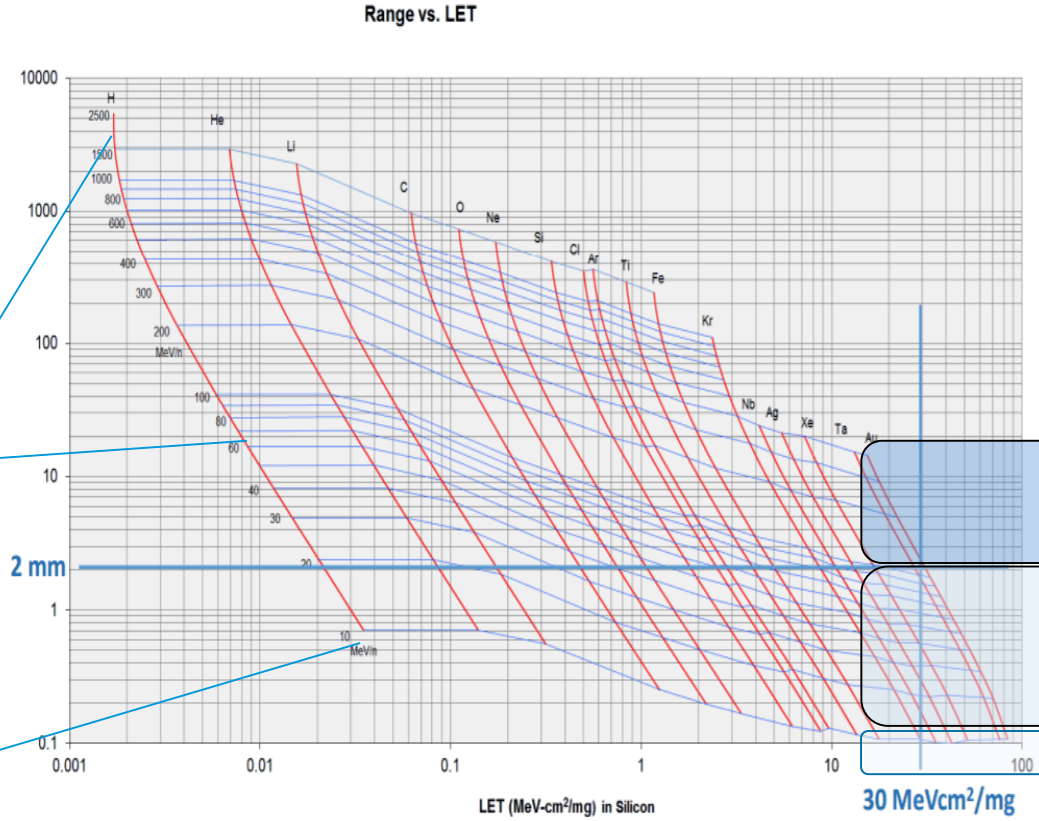
The exposure of either the dies of such packages is eiter impossible or difficult,
And there is the risk to modify the device response.

need of more enegetic particles to have more range (despite lower LET)

		
~700um **Flip chip:** Active area facing package Backside irradiation -> die thinning	~2mm **System in package:** Test separately	~500um **Dense structure:** Higher beam penetration range

Linear energy transfer and range

Facilities	Energy (MeV/nucleon)	Range of heavy species (Xe) in silicon
CERN CHARM	6-160 GeV/nucleon	meters
GSI SIS18	50 MeV/n to 1-1.5 GeV/n	2.4 mm to 7.8 cm
GANIL G4	27 to 60MeV/n	50 µm to 685 µm
KVI CART	30 MeV/n	333 µm
RADEF	22 MeV/n , 16.3 MeV/n, 9.3 MeV/n	255 µm 155 µm 92 µm
UCL HIF	8-10 MeV/n	73 µm



Very High energy

High energy

Standard energy

High energy facilities

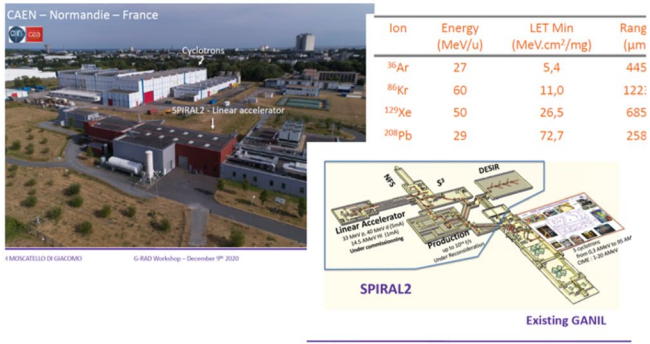
Europe

Facilities	Energy (MeV/nucleon)	Availability per year
GANIL G4 (Caen, France)	27 to 60 MeV/n	1-2 weeks
GSI SIS18 (Darmstadt, Germany)	50 MeV/n to 1-1.5 GeV/n	Less than 1 week Only scientific experiments

USA

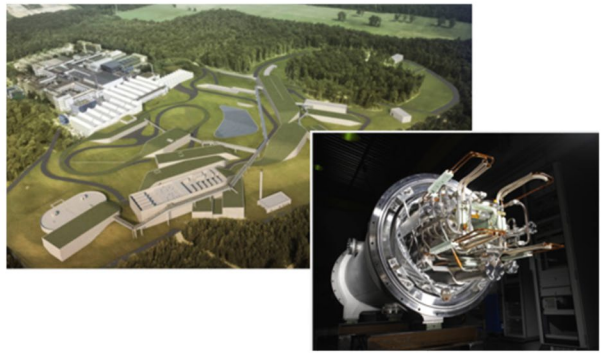
Facilities	Energy (MeV/nucleon)	Availability per year
TAMU (College Station, TX, USA)	15 MeV/n 25 MeV/n 40 MeV/n	About 20-25 weeks
NSRL (Brookhaven, USA)	1500-217 MeV/n (light to heavy ions)	~20 weeks NASA funded or scientific proposals

GANIL



After:
GRAND ACCELERATEUR NATIONAL D'IONS LOURDS
Marie-Hélène MOSCATELLO DI GIACOMO for the, G-RAD Workshop 2020

GSI



In this scenario, the European space industry is in a **critical competitive disadvantage due to the lack of radiation testing opportunities of High Energy Ion beams.**

Currently only facilities in USA offer **High Energy Ion beams**

Initiatives for Irradiation facilities in Europe

ESA initiatives:

Objectives:

Development of **high energy beam (range and LET, intensity)** for radiation tests of highly integrated electronic components **in existing facilities to** overcome the lack of beam availability to test complex EEE components

RADNEXT initiative:

RADNEXT is an H2020 INFRAIA-02-2020 infrastructure proposal with the objective of creating a network of facilities and related irradiation methodology for responding to the emerging needs of electronics component and system irradiation; as well as combining different irradiation and simulation techniques for optimizing the radiation hardness assurance for systems, focusing on the related risk assessment. => https://radnext-network.web.cern.ch/

Mitigation initiatives for COVID outbreak

Request to implement an infrastructure to cope with the situation

To execute test from remote, this to limit presence of number of visitors at the irradiation facility, and reduce travels

- -Full remote all setup installation and actions delegated to facility
- -Partial remote to reduced test-team presence at facility, with colleagues following from remote

Implementation (UCL, RADEF):

Communication between facility – remote user

Internet connection possibilities improved

Communication and screen sharing (Skype, Zoom, Teams and phone)

Webcams in the control area and inside of vacuum chamber

Monitoring on beam and equipment

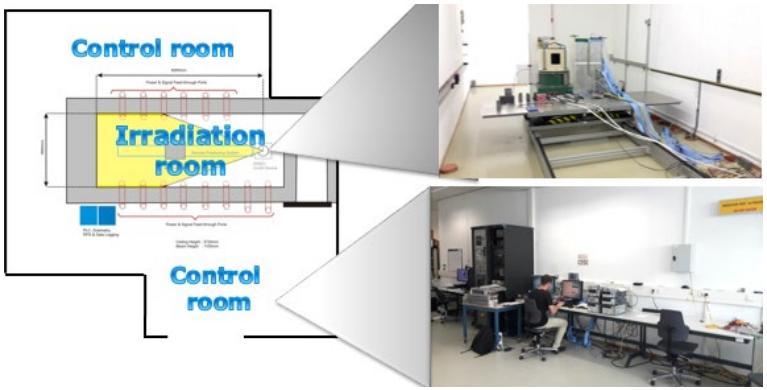
Streaming of beam status interface GUI (for RADEF possibility to control the HI beam status is in development)

Webcams and internet access to irradiation chambers

Note:

Full remote testing poses lots of limitations to the execution, can be considered only for very simple setups

ESTEC Facilities for irradiation test and test preparation



Co60 Facility

80 TBq Co60 source for Total Ionising Dose tests

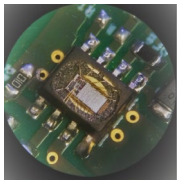
Dose rate window compliant with the ESCC22900 standard (from 0.01 rad/s [Si] to 3rad[Si]/s)

ISO17025 accredited dosimetry

Cf252 "CASE"

for qualitative investigation on SEE

thermal control of DUTs [-30 °C ; 130°C]



Decapsulation systems

For plastic packaging (Laser, mechanical, acid)

ESA Website for Radiation Test data

List of radiation test reports performed by ESA or European partners under ESA contracts

https://escies.org/labreport/radiationList

➔ New database to come (mid 2021)

HAS2 Proton TNID test	ON Semiconductors	HAS2	ON Semiconductor	02-05-2013	RA 0655			
HAS2 TID test	ON Semiconductors	HAS2	ON Semiconductor - SODERN	02-05-2013	RA 0656			
HAS2 electron tests	ON Semiconductors	HAS2	SODERN	02-05-2013	RA 0657			
HAS2 heavy ion test	ON Semiconductors	HAS2	SODERN	02-05-2013	RA 0658			
HAS2 Proton SET test	ON Semiconductors	HAS2	SODERN	02-05-2013	RA 0659			
ASIC and Microprocessors (4)								
SEE test report summary SCOC3 CD1034 - ATMEL ATC18RHA Spacecraft Controller On a Chip	ATMEL	SCOC3	EADS Astrium	01-01-2008	RA 0635			
Cf-252 testing of the LEON2-FT asic	Cobham Gaisler	LEON processor	Gaisler Research	10-07-2012	RA 0605			
GR740 System on chip	Cobham Gaisler	GR740, silicon revision 1 / Diffusion Lot nr: Q801934	Cobahm	24-05-2019	RA GR740-RADS-1-1-1			
Cf-252 testing of HIFAS asic	Omnisys	asic	Omnisys Instruments	01-01-2008	RA 0604			
CCD (1)								
Proton Testing at KVI	E2V	CCD204	n/a	01-01-2008	RA 0599			
FPGA (6)								
TID MFA-1 co-60	AMS	MFA-1	IWF / IIS	01-01-2008	RA 0513			
ATC18RHA TID ref.ADF-DE-R0564-CUP	ATMEL	ATC18RHA	ATMEL	31-03-2005	RA 0514			
ASIC Magnetometer Front End SEE	IWF + Fraunhofer	Magnetometer Front End	IWF	27-01-2006	RA 0545			
Single Event Transient Measurement - Microsemi A3P3000 FPGAs	Microsemi	A3P3000 FPGA	IROC	01-01-2008	RA 0707			
ProASIC3L FPGA SEE Test Report	Microsemi	A3PE3000L	Hirex	25-08-2011	RA 0584			
TID test on ProASIC3 FPGA from Microsemi (previously ACTEL)	Microsemi	A3PE3000L	n/a	20-02-2013	RA 0621			
GaAs/GaN (1)								
GaAs POWER DEVICES - MITSUBISHI MGF2430S - SUMITOMO FHX35LR -	NULL	NULL	n/a	01-01-2008	RA 0767			

TEC-QEC Contact Information

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alessandra.costantino@esa.int

ESCIES ESA Radiation webpage:
https://escies.org/webdocument/showArticle?id=227&groupid=6

Useful Links

https://escies.org/webdocument/showArticle?id=1068

Contacts for Beam info and requests

Info on external facilities

https://escies.org/webdocument/showArticle?id=921&groupid=6

e-mail: ERFbooking@esa.int

Info on ESTEC Co60

https://escies.org/webdocument/showArticle?id=251&groupid=6

e-mail: Co60.Facility.ESTEC@esa.int

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